Unit in mm

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

SSM6N04FU

HIGH SPEED SWITCH APPLICATIONS

With Built-in Gate-Source Resistor : $R_{GS} = 1 M\Omega$ (Typ.)

2.5 V Gate Drive

: $V_{th} = 0.7 \sim 1.3 \text{ V}$ Low Gate Threshold Voltage

Small Package

MAXIMUM RATINGS (Ta = 25°C) (Q1, Q2 COMMON)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	$ m v_{DS}$	20	V
Gate-Source Voltage	v_{GSS}	10	V
DC Drain Current	$I_{\mathbf{D}}$	100	mA
Drain Power Dissipation	P_{D}^{*}	200	mW
Channel Temperature	$\mathrm{T_{ch}}$	150	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	°C

Total Rating

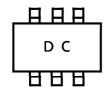
2.1 ± 0.1 1.25 ± 0.1 1.3 ± 0.1

SOURCE 1 4. SOURCE 2 GATE 2 GATE 1 US6 DRAIN 2 DRAIN 1

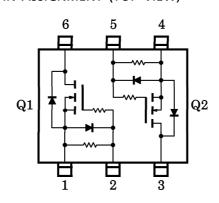
JEDEC EIAJ TOSHIBA 2-2J1C

Weight: 6.8 mg

MARKING



PIN ASSIGNMENT (TOP VIEW)



000707EAA2

TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.

In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..

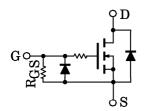
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FLECTRICAL	CHARACTERISTICS	/Ta -	25°C\	(O1	Ω^2	COMMON)
LLLCINICAL	CHANACILINISTICS	(ıa —	23 C)	101,	٧Z	COMMINION

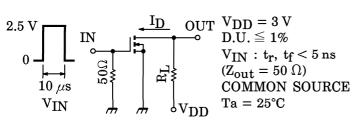
CHARACTERISTIC SYMBOL TEST CO		TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Gate Leakage	Current	I_{GSS}	$V_{GS} = 10 \text{ V}, \ V_{DS} = 0$	_	_	15	μ A
Drain-Source Voltage	Breakdown	V (BR) DSS	$I_D = 100 \mu\text{A}, \; V_{GS} = 0$	20	_	_	V
Drain Cut-off	Current	$I_{ m DSS}$	$V_{DS} = 20 \text{ V}, \ V_{GS} = 0$	_	_	1	μ A
Gate Thresho	ld Voltage	$V_{ m th}$	$ m V_{DS} = 3~V,~I_D = 0.1~mA$	0.7	_	1.3	V
Forward Tran	sfer Admittance	Y _{fs}	$V_{ m DS} = 3 m V, I_{ m D} = 10 m mA$	25	50	_	mS
Drain-Source	ON Resistance	R _{DS} (ON)	$I_D = 10 \text{ mA}, \ V_{GS} = 2.5 \text{ V}$	_	4	12	Ω
Input Capacit	ance	C_{iss}	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	11.0	_	pF
Reverse Trans	sfer Capacitance	$\mathrm{C}_{\mathrm{rss}}$	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	3.3	_	рF
Output Capac	eitance	Coss	$V_{DS} = 3 V, V_{GS} = 0, f = 1 MHz$	_	9.3	_	pF
Switching Time	Turn-on Time	ton	$V_{ m DD} = 3 m V, I_{ m D} = 10 m mA, \ V_{ m GS} = 0 {\sim} 2.5 m V$	_	0.16	_	
	Turn-off Time	t _{off}	$V_{ m DD} = 3 m V, I_{ m D} = 10 m mA, \ V_{ m GS} = 0 {\sim} 2.5 m V$	_	0.19	_	μ s
Gate-Source I	Resistor	RGS	$V_{GS} = 0 \sim 10 \text{ V}$	0.7	1.0	1.3	$\mathbf{M}\Omega$

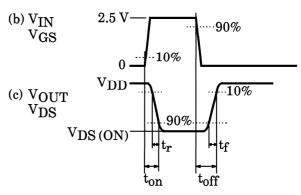
(Q1, Q2 COMMON) EQUIVALENT CIRCUIT



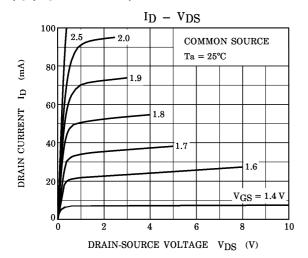
SWITCHING TIME TEST CIRCUIT

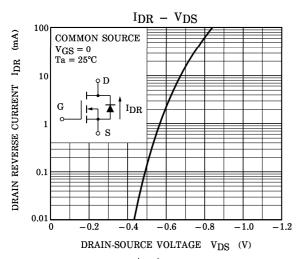
(a) TEST CIRCUIT

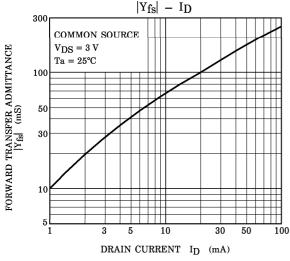


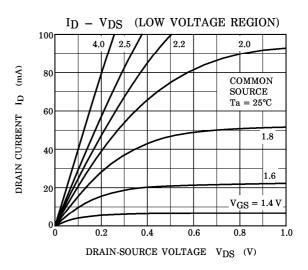


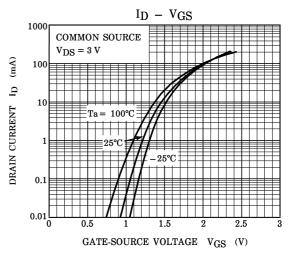
(Q1, Q2 COMMON)

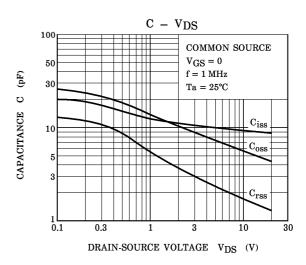




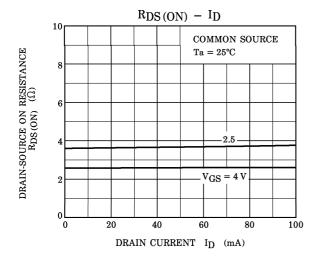


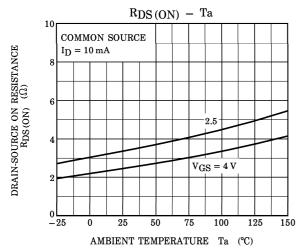


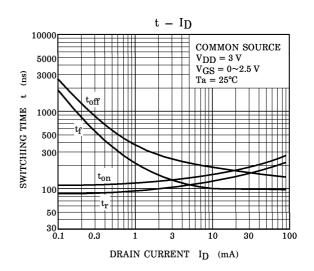


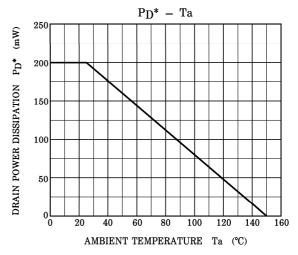


(Q1, Q2 COMMON)









*: Total Rating